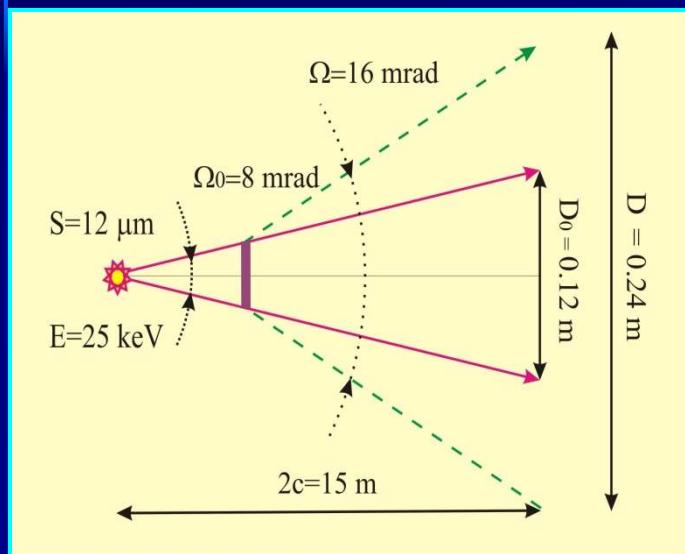




Studio di ottiche in riflessione e rifrazione per l'ottimizzazione del fascio Thomson

I.Bukreeva, A.Cedola, M.Fratini, A.Sorrentino,
S.Lagomarsino

Geometry of the optical system



Source

Source:	TS
Size of the source:	12 x 12 μm
Wavelength:	0.5 Å
Divergence Ω	8 mrad
Distance source – detector:	15 m
Area of illumination	0.12 m

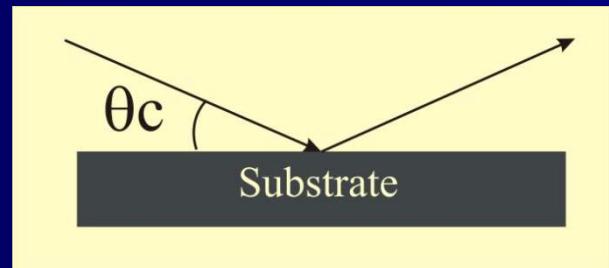
Goal

Increase divergence of the source and therefore
the area of illumination up to 0.24 m

X-ray reflective optics basic rules

Critical angle

The *index of refraction* for x-ray radiation is



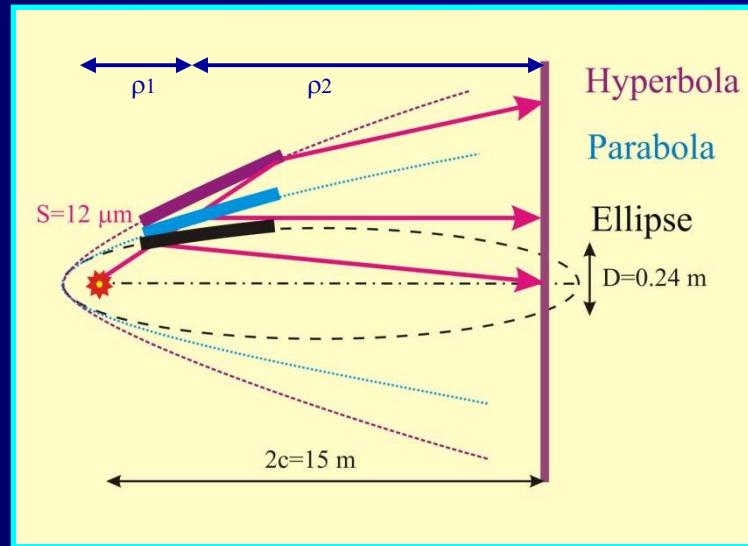
$$n = 1 - \delta - i\gamma \quad \gamma < \delta \ll 1 \rightarrow \operatorname{Re}(n) < 1$$

↓
Total reflection below a critical angle

$$\theta_c = (2\delta)^{1/2} \sim \lambda$$

$$\theta_c (Pt, \lambda=0.05 \text{ nm}) = 3.4 \text{ mrad} \ll \Omega = 8 \text{ mrad}$$

Geometry of grazing incidence optics



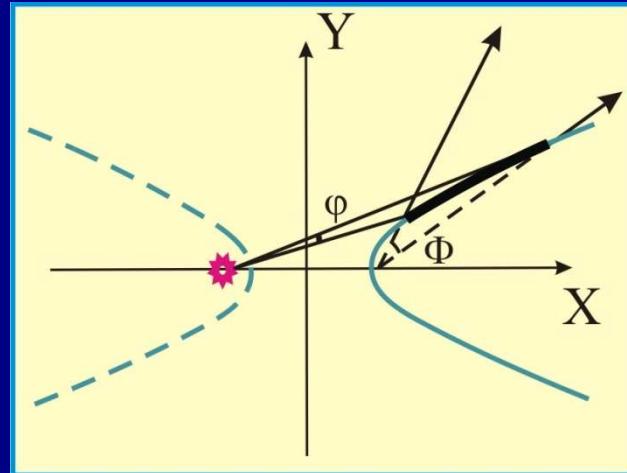
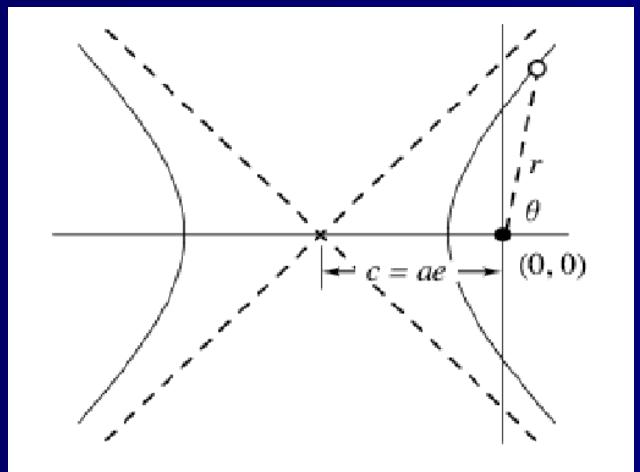
Ellipse

$$M = D/S \approx \rho_2 / \rho_1 = 2 \cdot 10^4 \Rightarrow \rho_1 \approx 7.5 \cdot 10^{-4} \text{ m}$$

Parabola

$$\Phi_{\max} = 2\theta_c \approx 7 \text{ mrad}$$
$$L \gg 1 \text{ m}$$

Hyperbolic reflecting mirror

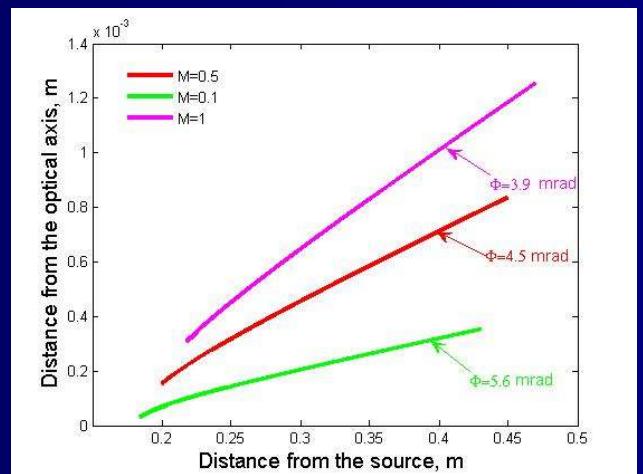
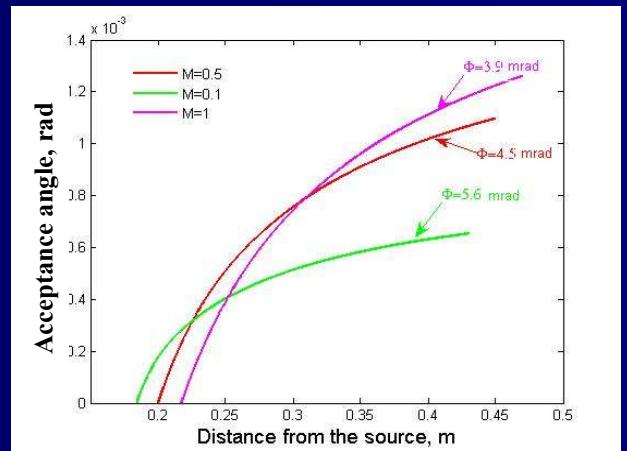


In polar coordinates centered at a focus,

$$r = \frac{a(e^2 - 1)}{1 - e \cos \theta},$$

All x-rays emitted from the source and reflected from the hyperbolic surface give a divergent beam having a secondary imaginary source

Hyperbolic reflecting mirror



Length of the mirror **L=0.25 m**
material **Pt**

Critical angle **3.4 mrad**

Eccentricity

$$e = 1 + \frac{1}{2} \theta_c^2 M$$

Acceptance angle increase with increase
of the eccentricity e

but

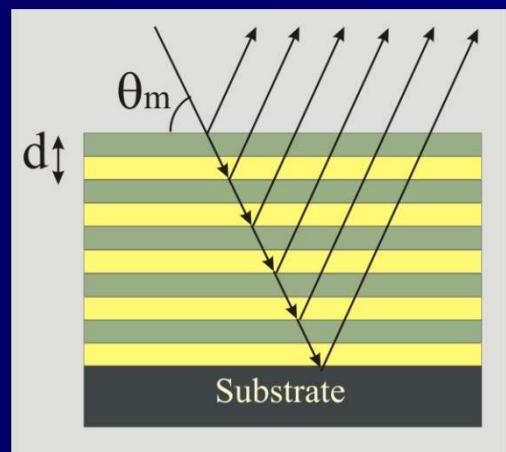
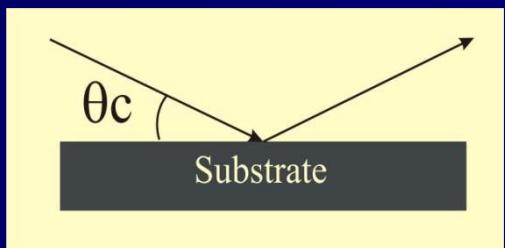
divergence Φ of the reflected beam
decrease therefore

$$e_{\text{opt}} = 1 + \frac{1}{2} \theta_c^2 M, \quad M = 0.5$$

Acceptance angle $< \theta_c = 3.4 \text{ mrad}$

$\beta_{\text{max}} \sim 1 \text{ mrad} \ll \Omega = 8 \text{ mrad}$

Short-period multilayers



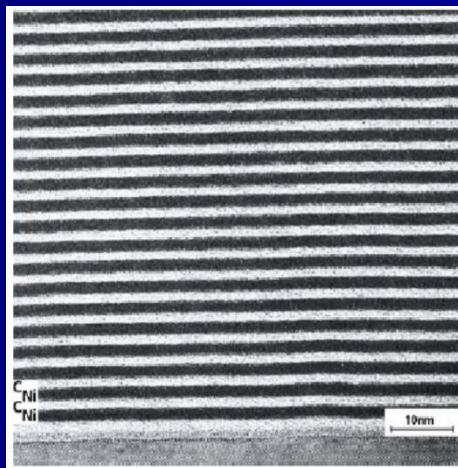
Critical angle

$$\theta_c = (\delta)^{1/2} \quad \varepsilon = 1 - \delta + i\gamma \quad \gamma \ll \delta \ll 1$$

$$\theta_c \text{ (Pt, } \lambda = 0.05 \text{ nm)} = 3.4 \text{ mrad} \ll \Omega = 8 \text{ mrad}$$

Multilayer mirror

$$2d \sin(\theta_m) = m\lambda \quad \rightarrow \quad d = 2-3 \text{ nm}$$
$$\theta_i = 8-12 \text{ mrad}$$



Ni / C $d = 3.15 \text{ nm}$

R.Dietsh, S.Braun, T.Holz, H.Mai,
R.Scholz, L.Brugemann
“Multilayer x-ray optics for energy
 $E > 8 \text{ keV}$ and their application in x-ray
analysis” SPIE

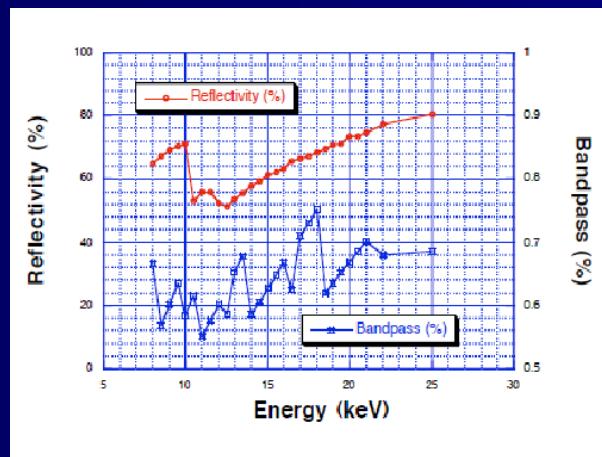
Short-period multilayers

Multilayer (0.965 nm WSi2)/(1.005 nm Si)
 $d=2$ nm

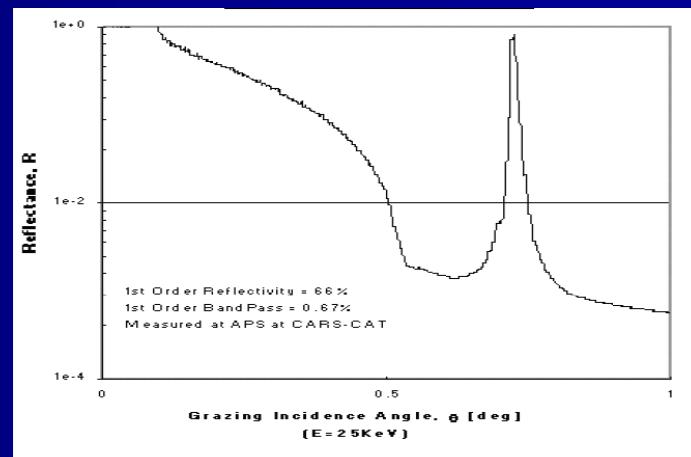
$\theta_1=12.5$ mrad

Advantage of WSi2/Si multilayer
High temperature and radiation load stability

C.Liu, R.Conley, A.T.Macrander, T.Grabер,
Ch.Morawe,C.Borel, E.M.Dufresne,
"Small-d-spacing WSi2/Si narrow bandpass multilayers"
Proc. SPIE, Vol. 5537, 154 (2004)

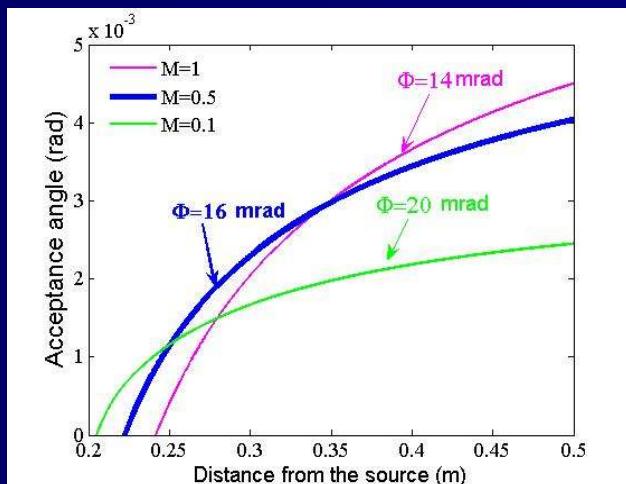
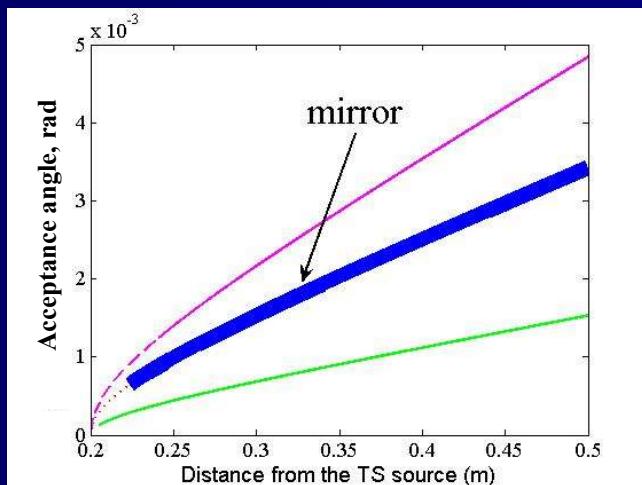


Simulated reflectivity and bandpass for
WSi2/Si ($d=2$ nm) $\times 300$ multilayer
 $R(E=25\text{ keV}) = 80\%$



Reflectivity scan carried out at the
ChemMatCARS-CAT of the APS at 25 keV
 $R(E=25\text{keV})=66\%$, bandpass 0.67%

Hyperbolic reflecting mirror



Length of the mirror $L=0.25$ m

WSi₂/Si multilayer

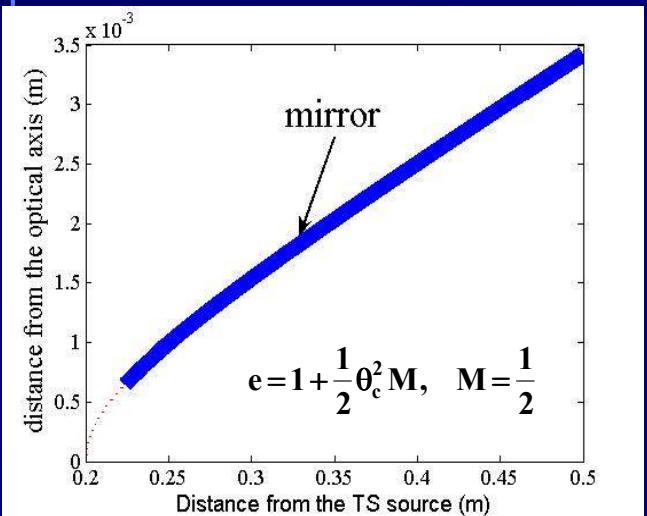
$\theta_1=12.5$ mrad

Eccentricity $e = 1 + \frac{1}{2}\theta_1^2 M$, $M = 0.5$

Acceptance angle

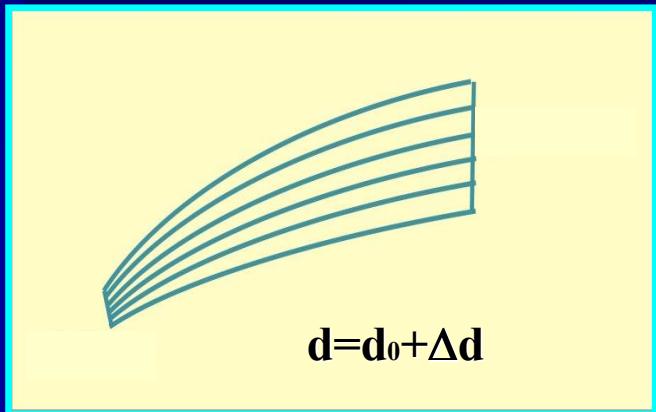
$\beta_{\max} \sim 4$ mrad = $\Omega/2$

Hyperbolic reflecting mirror



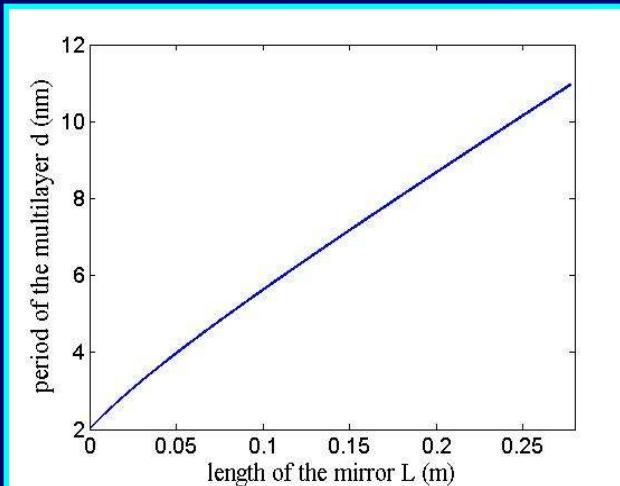
Optical system (hyperbolic)

Critical angle (multilayer):	8-12.5 mrad
Distance source – mirror:	0.2 m
Length of mirrors:	0.25 m
Divergence Φ	16.4 mrad = 2W
Area of illumination	0.24 m
Acceptance angle:	4 mrad

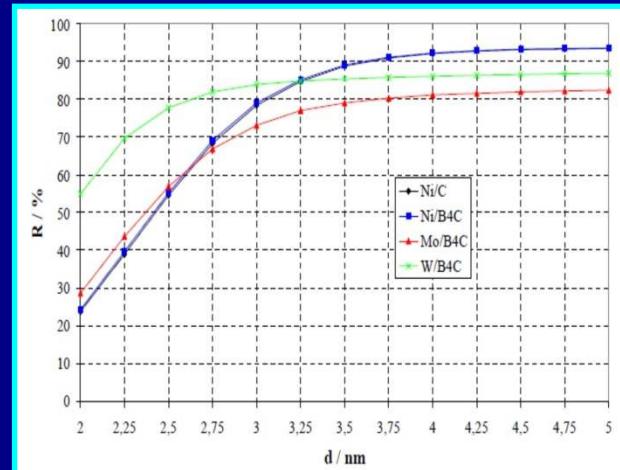


Surface of the mirror is covered by
laterally graded multilayers

Laterally graded multilayers

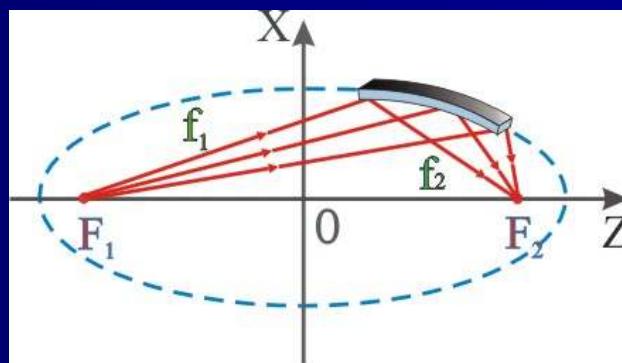
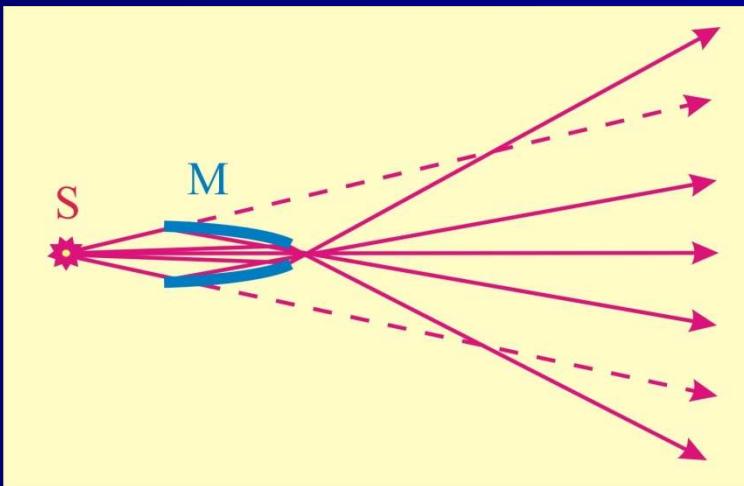


Period of the multilayer increase

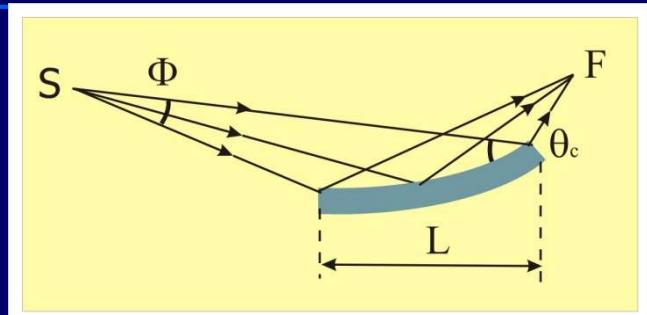


Simulation of the reflectivities of
Ni/C, Ni/B₄C, Mo/B₄C, and W/B₄C
multilayer systems with 75 periods
for E=30 keV radiation
 $R(d>3.5 \text{ nm}) \rightarrow 80\text{-}90 \%$

Elliptical focusing mirrors



Elliptical focusing mirrors



$$e_{opt} = 1 - \frac{1}{2} \theta_c^2 M \quad M = \frac{1}{2}$$

$$\Phi_{opt} \approx 5 / 6 \theta_c M$$

$$L_{opt} \approx 2c \left(1 - \frac{2 - \sqrt{1 + M}}{1 + M} \right)$$

2 mirror or ellipsoid

Divergence ~ 16 mrad

Material Pt

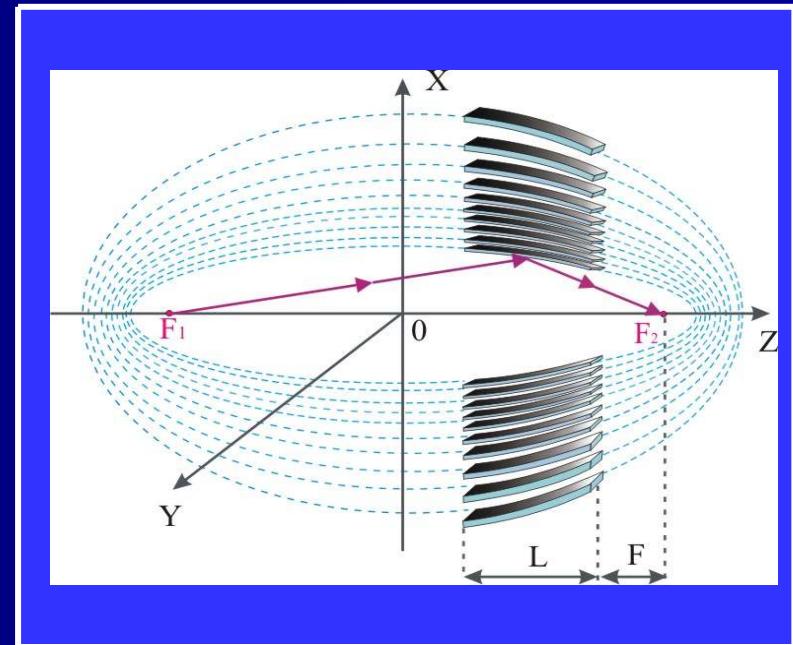
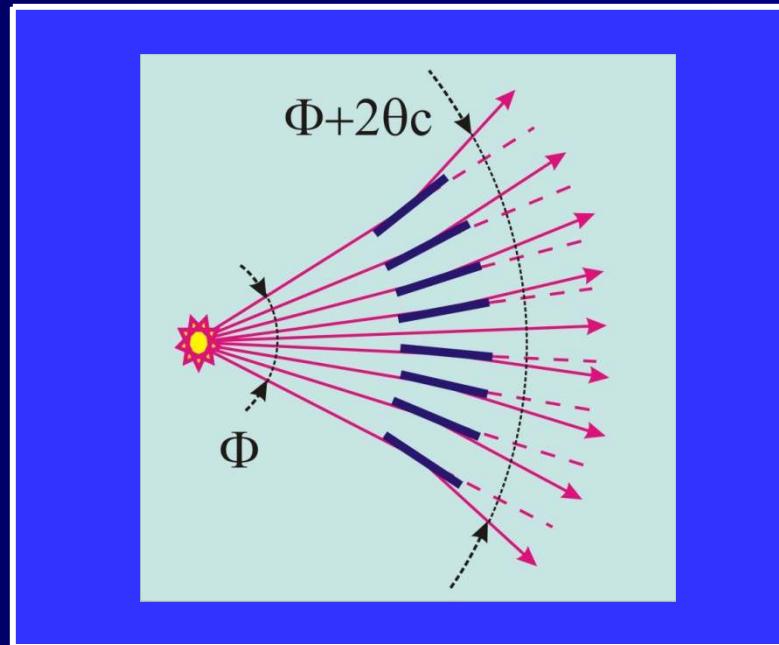
Distance source –mirror:	1 m
Critical angle:	3.4 mrad
Acceptance angle (Φ_{opt})	1.4 mrad
Length of the mirrors:	~ 1 m
Divergence	~ 3 mrad

Distance	0.2 m
Acceptance angle	1.4 mrad
Length of the mirror	~ 0.2 m
Divergence	~ 3 mrad

Multilayer

Resonance angle (θ_1)	8-12.4 mrad
Acceptance angle (Φ_{opt})	4.6 mrad
Distance	1m
Length of the mirror	0.97 m
Divergence	$\sim 8-10$ mrad
Distance	0.2 m
Acceptance angle (Φ_{opt})	4.6 mrad
Length of the mirror	~ 0.2 m
Divergence	$\sim 8-10$ mrad

Multiple mirrors



$$\theta_c(Pt)=3.4 \text{ mrad} \quad \Phi_0=\Phi+4\theta \sim 16 \text{ mrad}$$

$$D \sim 15 \text{ m} * 16 \text{ mrad} \sim 0.24 \text{ m}$$

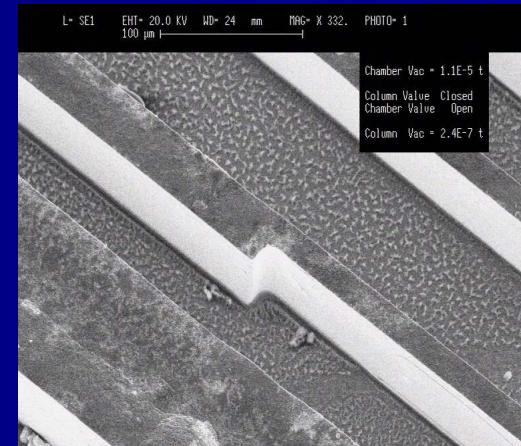
*I.Bukreeva, A.Gerardino, A.Surpi, A.Cedola,
 S.Dabagov, S.Lagomarsino,
 Design and simulation of nested x-ray mirrors,
 Proc. SPIE, vol. 5974 (2005).*

*I.Bukreeva, A. Surpi, A. Gerardino,
 S.Lagomarsino, F. Perennes, M. Altissimo,
 S. Cabrini, A. Carpentiero, A. Vicenzo and
 P. Cavallotti, Multiple micro mirrors for X-ray
 focusing and collimation, Optics Communications,
 259, 366- 372, (2006).*

Experimental results with deep X-ray lithography



- 4 mirror system for synchrotron radiation
- Mirrors in Ni grown by electrochemical deposition



Experimental results with SU8



- Few-centimeter long self-standing mirrors
- No enlargement in the process

